

ETHERNET TESTING SERVICES

Embedded MAU Test Suite
Version 4.1
Technical Document



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MODIFICATION RECORD

- July 20, 2004 **Version 4.1 Released**
Modifications since last release:
 - Updated cover page with IOL logo
 - Reworded test 14.3.3 to reflect the correct procedure
- January 3, 2002 **Version 4.0 Released**
Modifications since last release:
 - Updated to IEEE Std. 802.3, 2000 Edition
 - Removed Test 14.1.9, TD Circuit Common-Mode Output Voltage
- June 30, 1999 **Version 3.3 Released**
Modifications since last release:
 - Renumbered all tests to reflect numbering scheme employed by Fast Ethernet Consortium reports.
 - Restructured test sequences to follow listing of test cases in 1803.3d-1993 supplement.
 - Added Test 14.1.1, TP_IDL Silence Duration and Silence Voltage
 - Added Test 14.1.9, TD Circuit Common-Mode Output Voltage

New structure:

 - Transmit Functions and Transmitter Specifications
 - 14.1.1 TP_IDL, Silence Duration and Silence Voltage
 - 14.1.2 TD Short Circuit Fault Tolerance
 - 14.1.3 Peak Differential Output Voltage on the TD Circuit
 - 14.1.4 Harmonic Content, All Ones (or all zeroes) Signal
 - 14.1.5 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template
 - 14.1.6 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template (inverted template)
 - 14.1.7 Transmitter Waveform for Start of TP_IDL with Specified Loads, with and without the Twisted Pair Model
 - 14.1.8 TD Circuit Differential Output Impedance
 - 14.1.9 TD Circuit Common-Mode Output Voltage
 - 14.1.10 Link Test Pulse Waveform, with Specified Loads, with and without TPM
 - 14.1.11 Transmitter Output Timing Jitter with Twisted Pair Model
 - 14.1.12 Transmitter Output Timing Jitter without Twisted Pair Model
 - Receiver Functions and Receiver Specifications
 - 14.2.1 RD Short Circuit Fault Tolerance
 - 14.2.2 RD Circuit Signal Acceptance
 - 14.2.3 RD Circuit Differential Input Impedance
 - 14.2.4 RD Circuit Link Test Pulse Acceptance
 - Link Integrity Test Functions
 - 14.3.1 Link Loss Timer
 - 14.3.2 Acceptance Range for Consecutive Link Test Pulses
 - 14.3.3 Link Test Pulses Outside Acceptance Range (not in the Link Test Pass state)
 - 14.3.4 Value of "lc_max"
 - 14.3.5 Link Fail Effect on Transmit Functions
 - 14.3.6 Link Fail Effect on Receive Functions
- March 26, 1998 **Version 3.2 Released**
Modifications since last release:
 - Removed Test 9.14, Signaling Rate during Transmission of Preamble
- October 17, 1997 **Version 3.1 Released**
Modifications since last release:
 - Added Test 9.14, Signaling Rate during Transmission of Preamble
- August 20, 1997 **Version 3.0 Released**
Modifications since last release:
 - Removed Test 8.14, Power Cycle Effect on the TD Circuit (not accurate)
 - Added Test 11.14, TD Circuit Differential Output Impedance

Added Test 15.14, RD Circuit Differential Input Impedance
Other tests renumbered accordingly:

- Test Group 1: Transmit Functions and Transmit Specifications
 - 1.14 TD Short Circuit Fault Tolerance
 - 2.14 Transmitter Waveform for Start of TP_IDL with Specified Loads, with and without the Twisted Pair Model
 - 3.14 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template
 - 4.14 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template (inverted template)
 - 5.14 Peak Differential Output Voltage on the TD Circuit
 - 6.14 Transmitter Output Timing Jitter with Twisted Pair Model
 - 7.14 Transmitter Output Timing Jitter without Twisted Pair Model
 - 9.14 Harmonic Content, All Ones (or all zeroes) Signal
 - 10.14 Link Test Pulse Waveform, with Specified Loads, with and without TPM
 - 11.14 TD Circuit Differential Output Impedance
- Receiver Functions and Receiver Specifications
 - 12.14 RD Short Circuit Fault Tolerance
 - 13.14 RD Circuit Signal Acceptance
 - 14.14 RD Circuit Link Test Pulse Acceptance
 - 15.15 RD Circuit Differential Input Impedance
- Link Integrity Test Functions
 - 16.14 Link Loss Timer
 - 17.14 Acceptance Range for Consecutive Link Test Pulses
 - 18.14 Link Test Pulses Outside Acceptance Range (not in the Link Test Pass state)
 - 19.14 Value of "lc_max"
 - 20.14 Link Fail Effect on the Transmit Functions
 - 21.14 Link Fail Effect on the Receive Functions

- September 6, 1996

Version 2.0 Released

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Added Test 19.14, Link Fail Effect on the Receive Functions

- August 9, 1996

Version 1.1 Released

Modifications since last revision:

Test 13.14 added more link test pulse shapes not previously defined

- February 9, 1996

Version 1.0 Released

Initial Release

- Test Group 1: Transmit Functions and Transmit Specifications
 - 1.14 TD Short Circuit Fault Tolerance
 - 2.14 Transmitter Waveform for Start of TP_IDL with Specified Loads, with and without the Twisted Pair Model
 - 3.14 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template
 - 4.14 Differential Output Waveform on the TD Circuit with Scaling of Voltage Template (inverted template)
 - 5.14 Peak Differential Output Voltage on the TD Circuit
 - 6.14 Transmitter Output Timing Jitter with Twisted Pair Model
 - 7.14 Transmitter Output Timing Jitter without Twisted Pair Model
 - 8.14 Power Cycle Effect on the TD Circuit
 - 9.14 Harmonic Content, All Ones (or all zeroes) Signal
 - 10.14 Link Test Pulse Waveform, with Specified Loads, with and without TPM
- Receiver Functions and Receiver Specifications
 - 11.14 RD Short Circuit Fault Tolerance
 - 12.14 RD Circuit Signal Acceptance
 - 13.14 RD Circuit Link Test Pulse Acceptance
- Link Integrity Test Functions
 - 14.14 Link Loss Timer
 - 15.14 Acceptance Range for Consecutive Link Test Pulses
 - 16.14 Link Test Pulses Outside Acceptance Range (not in the Link Test Pass state)
 - 17.14 Value of "lc_max"
 - 18.14 Link Fail Effect on the Transmit Functions

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INTRODUCTION

Overview

The University of New Hampshire's InterOperability Laboratory (IOL) is an institution designed to improve the interoperability of standards based products by providing an environment where a product can be tested against other implementations of a standard. This suite of tests has been developed to help implementers evaluate the functioning of their Clause 14 Medium Attachment Unit, Type 10BASE-T based products. The tests do not determine if a product conforms to the IEEE 802.3 standard, nor are they purely interoperability tests. Rather, they provide one method to isolate problems within 10BASE-T physical layer device. Successful completion of all tests contained in this suite does not guarantee that the tested device will operate with other Clause 14 10BASE-T MAUs. However, combined with satisfactory operation in the IOL's interoperability test bed, these tests provide a reasonable level of confidence that the Device Under Test (DUT) will function well in most 10BASE-T environments.

Organization of Tests

The tests contained in this document are organized to simplify the identification of information related to a test and to facilitate in the actual testing process. Each test contains an identification section that describes the test and provides cross-reference information. The discussion section covers background information and specifies why the test is to be performed. Tests are grouped in order to reduce setup time in the lab environment. Each test contains the following information:

Test Number

The Test Number associated with each test follows a simple grouping structure. Listed first is the Test Group Number followed by the test's number within the group. This allows for the addition of future tests to the appropriate groups of the test suite without requiring the renumbering of the subsequent tests.

Purpose

The purpose is a brief statement outlining what the test attempts to achieve. The test is written at the functional level.

References

The references section lists cross-references to the IEEE 802.3 standards and other documentation that might be helpful in understanding and evaluating the test and results.

Resource Requirements

The requirements section specifies the hardware, and test equipment that will be needed to perform the test. The items contained in this section are special test devices or other facilities, which may not be available on all devices.

Last Modification

This specifies the date of the last modification to this test.

Discussion

The discussion covers the assumptions made in the design or implementation of the test as well as known limitations. Other items specific to the test are covered here.

Test Setup

The setup section describes the configuration of the test environment. Small changes in the configuration should be included in the test procedure.

Procedure

The procedure section of the test description contains the step-by-step instructions for carrying out the test. It provides a cookbook approach to testing, and may be interspersed with observable results.

Observable Results

The observable results section lists observables that can be examined by the tester to verify that the DUT is operating properly. When multiple values are possible for an observable, this section provides a short discussion on how to interpret them. The determination of a pass or fail for a certain test is often based on the successful (or unsuccessful) detection of a certain observable.

Possible Problems

This section contains a description of known issues with the test procedure, which may effect test results in certain situations.

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GROUP 1: TRANSMIT FUNCTIONS AND TRANSMIT SPECIFICATIONS

Scope: The following tests cover 10BASE-T operation specific to transmission characteristics on the TD circuit.

Overview: These tests are designed to verify that the device under test transmits various defined waveforms properly and to verify transmitted signal parameters.

Test #14.1.1: TP_IDL, Silence Duration and Silence Voltage

Purpose: To verify the timing of signals following the start of TP_IDL.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.1, Test Case ID 1411.01.06
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probes
- TP Test Card

Last Modification: July 30, 1999.

Discussion: Once a device has sourced a start of TP_IDL signal from the TD circuit, it should be followed by a 16 ms \pm 8 ms period of silence and a link test pulse.

Test Setup: Set-up the devices as shown in Fig. 14.1.1-1. The TP test card is used for LTP generation and line termination for the DUT's TD circuit. The TD circuit should be terminated with either of the test loads defined in Figure 14-11 in the IEEE 802.3 standard. Observations of the TD circuit are made with differential probes across the circuit termination. The TP test card additionally contains a Twisted Pair Model which may be added to the TD circuit before termination.

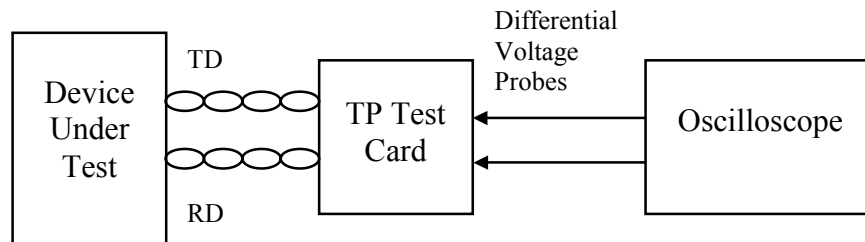


Figure 14.1.1-1: Test Setup A

Procedure:

1. While sourcing data from the TD circuit, terminate it with a 100 Ω resistive load.
2. Measure the period of time from the start of TP_IDL to the next transmitted link test pulse.
3. Measure the period of time between repeating link test pulses.
4. Measure the differential voltage during TD circuit silence between link test pulses.

Observable Results:

- The measured time period between start of TP_IDL and first link test pulse shall be 16 ms \pm 8 ms.
- All repeating link test pulses shall be transmitted every 16 ms \pm 8 ms.
- The differential voltage of the TD circuit shall remain at 0 mV \pm 50 mV during the periods of silence (time between link test pulses).

Test #14.1.2: TD Short Circuit Fault Tolerance

Purpose: To verify transmitter tolerance to short circuits.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.01
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.7

Resource Requirements:

- Current probe
- Oscilloscope

Last Modification: February 9, 1996

Discussion: Transmitters shall be able to withstand short circuits for indefinite periods of time without suffering damage. After such a fault is removed, normal operation of the transmitter shall resume.

Test Setup: Set-up the devices as shown in Fig. 14.1.2-1. The TP test card is used for LTP generation.

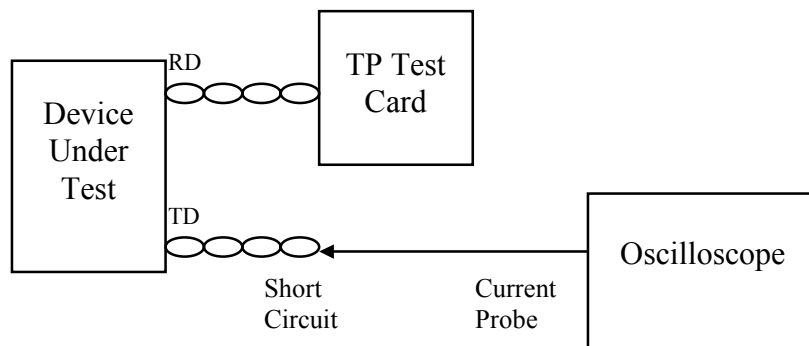


Figure 14.1.2-1: Test Setup B

Procedure:

1. Supply power to the device under test.
2. Apply a short circuit across the TD circuit for 10 seconds.
3. Monitor the peak output current of the TD circuit.
4. Continue to monitor the output current for an additional 10 seconds while trying to source data from the TD circuit.
5. Remove the short circuit.
6. Verify that the transmitter operates normally by performing other transmitter tests.

Observable Results:

- The magnitude of the current going through the short circuit shall not exceed 300 mA.
- The station under test shall function properly during other transmitter tests.

Test #14.1.3: Peak Differential Output Voltage on the TD Circuit

Purpose: To verify the peak differential output voltage on the TD circuit.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.02
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probes
- TP Test Card

Last Modification: February 9, 1996

Discussion: The peak differential voltage output on a TD circuit shall be between 2.2 V and 2.8 V for all data sequences when terminated with a 100 Ω resistive load.

Test Setup: See Figure 14.1.1-1.

Procedure:

5. While sourcing data from the TD circuit, terminate it with a 100 Ω resistive load.
6. Measure the peak differential output voltage across the TD circuit.

Observable Results:

- The measured peak differential voltage across the TD circuit shall fall between 2.2 V and 2.8 V.

Test #14.1.4: Harmonic Content, All Ones (or All Zeroes) Signal

Purpose: To verify the harmonic content of the output signal.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.03
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: When monitoring a series of all ones (or all zeroes) on the TD circuit, each harmonic shall be at least 27 dB below the 10 MHz fundamental.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. Source data from the TD circuit.
2. Find a portion of the packet which contains 20 cycles of all ones (or all zeroes).
3. Use the FFT function of the oscilloscope to measure the frequency components of the signal. A Blackman-Harris window and source averaging shall be used.

Observable Results:

- All of the harmonics shall be at least 27 dB below the fundamental.

Test #14.1.5: Differential Output Waveform on the TD Circuit with Scaling of Voltage Template.

Purpose: To verify that the transmitter output equalization meets standard specifications.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.04
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: The eye pattern sourced from the TD circuit shall conform to defined templates.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. While sourcing data from the TD, terminate it with a 100 Ω resistive load and with the TPM.
2. Accumulate an eye pattern on the oscilloscope with the triggering set to zero volts and a positive slope.

Observable Results:

- The eye pattern sourced from the TD circuit shall fit into the template shown in Figure 14-9 of IEEE 802.3.

Test #14.1.6: Differential Output Waveform on the TD Circuit with Scaling of Voltage Template (inverted template)

Purpose: To verify that the transmitter output equalization meets standard specifications.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.05
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: The eye pattern sourced from the TD circuit shall conform to defined inverted templates.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. While sourcing data from the TD circuit, terminate it with the TPM and a 100 Ω resistive load.
2. Accumulate an eye pattern on the oscilloscope with the triggering set to zero volts and a negative slope.

Observable Results:

- The eye pattern sourced from the TD circuit shall fit into the template shown in Figure 14-9 of IEEE 802.3.

Test #14.1.7: Transmitter Waveform for Start of TP_IDL with specified loads, with and without the Twisted Pair Model

Purpose: To verify that the transmitter functions properly after a transition to the idle state.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.06
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: After the transmission of a packet, a TP_IDL signal is transmitted. This start of TP_IDL signal shall fit into a defined template.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. Monitor the TD circuit while data packets are being transmitted.
2. Observe the TP_IDL waveforms at the end of the packets across each test load defined in Figure 14-11.
3. Repeat procedure with the loads connected through the TPM.

Observable Results:

- The observed TP_IDL pattern shall fit into the template defined in Figure 14-10 of IEEE 802.3 for all test loads, with or without the TPM.
- After the voltage has gone below -50 mV, it shall remain below +50 mV during the TP_IDL waveform.

Test #14.1.8: TD Circuit Differential Output Impedance

Purpose: To verify the transmitter differential output impedance.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.07
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.2

Resource Requirements:

- Network Analyzer
- Balun

Last Modification: August 20, 1997

Discussion: Whenever the MAU is powered, the differential output impedance, as measured on the TD circuit, must meet the following specifications: Any reflection on the TD circuit of a simplex link segment having any impedance between 85 Ω and 111 Ω must be at least 15 dB below the incident over the frequency range of 5.0 MHz to 10 MHz.

Test Setup: Set-up the devices as shown in Figure 14.1.8-1. The balun is used to convert the 50 Ω unbalanced output from the network analyzer to the 100 Ω balanced UTP cable.

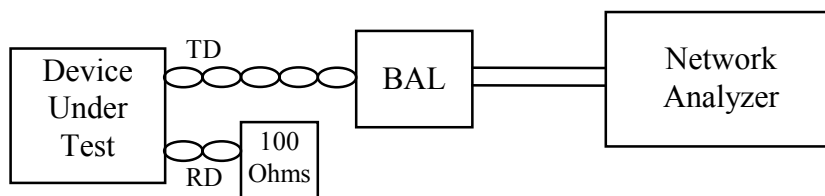


Figure 14.1.8-1: Test Setup C

Procedure:

1. Calibrate the network analyzer with the balun and twisted pair cable between the analyzer and the calibration loads.
2. Connect the TD circuit of the DUT to the twisted pair cable and terminate the RD circuit with a 100 Ω resistive load. Be sure the DUT is powered on.
3. Set the network analyzer to calculate return loss from 5.0 MHz to 10 MHz at its reference resistance.
4. Use the analyzer data to calculate the return loss for reference resistances of 100 Ω , 85 Ω , and 111 Ω .

Observable Results:

- The return loss for the TD circuit must be at least 15 dB below the incident from the range of 5.0 MHz to 10 MHz for each of the reference resistances: 100 Ω , 85 Ω , and 111 Ω .

Test #14.1.9: Link Test Pulse Waveform, with Specified Loads, with and without TPM

Purpose: To verify that the link test pulse waveforms meet specification.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.11
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: There are waveform specifications in IEEE 802.3 to which all link test pulses need to conform. This test is designed to verify that the station under test produces link test pulses within specification.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. Monitor the TD circuit while no data is being transmitted.
2. Observe the link test pulse waveforms on the TD circuit across each test load defined in Figure 14-11.
3. Repeat procedure with the loads connected through the TPM.

Observable Results:

- Under each test setup, the link test pulse waveforms shall fit within the template defined in Figure 14-12.
- After the differential output voltage drops below -50 mV, it shall remain below +50 mV.

Test #14.1.10: Transmitter Output Timing Jitter with Twisted Pair Model

Purpose: To verify that the timing of zero crossings on the TD circuit occurs within specification.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.12
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.3, B.4.1, B.4.3.3

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: All zero crossings of the TD signal shall occur with timing specification. This is verified by measuring the zero crossings at 8.0 and 8.5 bit times (BT) and making sure these times fit within specification. This test does not apply to the first bit transmitted, so this bit is disregarded.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. While sourcing data from the TD circuit, terminate it with a 100 Ω resistive load and with the TPM.
2. Set the oscilloscope to trigger at zero voltage and a positive slope.
3. While sourcing data, use the oscilloscope to measure the output timing jitter of the TD circuit.
4. Observe the zero crossings at 8.0 and 8.5 BT after the triggering zero crossing.

Observable Results:

- Zero crossings shall occur at 8.0 BT \pm 11 ns and 8.5 BT \pm 11 ns after the triggering zero crossing.

Test #14.1.11: Transmitter Output Timing Jitter without Twisted Pair Model

Purpose: To verify that the timing of zero crossings on the TD circuit occurs within specification.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.10, Test Case ID 1411.10.13
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.2.3, B.4.1, B.4.3.3

Resource Requirements:

- Oscilloscope
- Differential Output Probe
- TP Test Card

Last Modification: February 9, 1996

Discussion: All zero crossings of the TD signal shall conform with timing standards. This is verified by measuring the zero crossings at 8.0 and 8.5 bit times (BT) and making sure these times fit within specification. This test does not apply to the first bit transmitted, so this bit is disregarded.

Test Setup: See Figure 14.1.1-1.

Procedure:

1. While sourcing data from the TD circuit, terminate it with a 100 Ω resistive load but without the TPM.
2. Set the oscilloscope to trigger at zero voltage and a positive slope.
3. While sourcing data, use the oscilloscope to measure the output timing jitter of the TD circuit.
4. Observe the zero crossings at 8.0 and 8.5 BT after the triggering zero crossing.

Observable Results:

- Zero crossings shall occur at 8.0 BT \pm 20 ns and 8.5 BT \pm 20 ns after the triggering zero crossing.

GROUP 2: RECEIVER FUNCTIONS AND RECEIVER SPECIFICATIONS

Scope: The following tests cover 10BASE-T operation specific to reception functionality of the DUT.

Overview: These tests are designed to ensure correct input signal handling of the receiver.

Test #14.2.1: RD Circuit Short Circuit Fault Tolerance

Purpose: To verify receiver tolerance to short circuits.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.11, Test Case ID 1411.11.01
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.3.6

Resource Requirements:

- None

Last Modification: February 9, 1996

Discussion: The RD circuit shall be able to withstand short circuits.

Test Setup: All that is needed is to plug a simple RJ-45 plug with a short across the RD pair into the port of the DUT.

Procedure:

1. Apply a short circuit across the RD circuit for 10 seconds.
2. Verify that the station under test still works by performing the other receiver tests.

Observable Results:

- The station under test shall perform normally for the remainder of the testing.

Test #14.2.2: RD Circuit Signal Acceptance

Purpose: To verify the receiver's differential input voltage acceptance range.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.11, Test Case ID 1411.11.03
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.3.1

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: The IEEE 802.3 standard requires that a station accepts packets with a maximum jitter allowance of 13.5 ns. This means that wide pulses may have 73 ns to 127 ns between zero crossings and narrow pulses may have 23 ns to 77 ns. This is to account for a maximum jitter allowance of ± 13.5 ns. Also, these packets may be received at a differential voltage between 585 mV and 3.1 V.

Test Setup: Set-up the devices as shown in Fig. 14.2.2-1. The arbitrary waveform generator produces the test signals for the RD circuit. The balun is used to convert the 50 Ω unbalanced AWG output to a 100 Ω balanced UTP output onto the RD circuit. Observations of the TD circuit are made with differential probes across the 100 Ω termination on the TP test card.

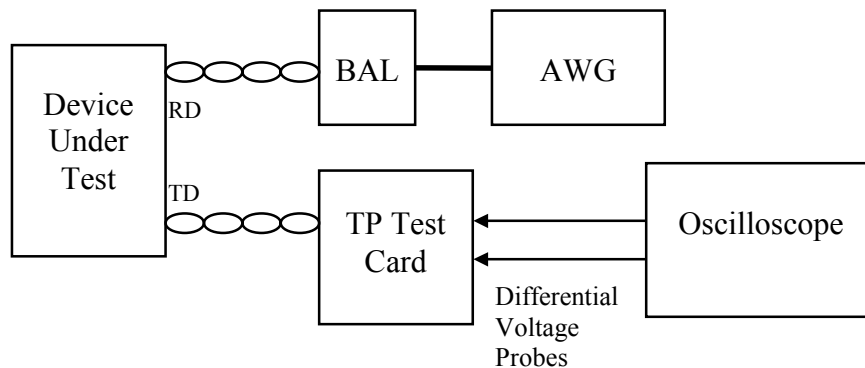


Figure 14.2.2-1: Test Setup E

Procedure:

1. Use the AWG to generate a packet with both maximum jittered wide and narrow pulses.
2. Send this packet at a differential amplitude of 585 mV and 3.1 V.
3. Monitor the TD circuit.

Observable Results:

- If the DUT is set to reply to the packet sent, a reply shall be observed on the TD circuit for both voltage levels.
- If MAC layer statistics can be observed, the reception of a good packet shall be logged for both voltage levels.

Test #14.2.3: RD Circuit Differential Output Impedance

Purpose: To verify the receiver differential input impedance.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.11, Test Case ID 1411.11.05
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.3.4

Resource Requirements:

- Network Analyzer
- Balun

Last Modification: August 20, 1997

Discussion: Whenever the MAU is powered, the differential input impedance, as measured on the RD circuit, must meet the following specifications. Any reflection on the RD circuit of a simplex link segment having any impedance between 85 Ω and 111 Ω must be at least 15 dB below the incident over the frequency range of 5.0 MHz to 10 MHz.

Test Setup: Set-up the devices as shown in Figure 16.14-1. The balun is used to convert the 50 Ω unbalanced output from the network analyzer to the 100 Ω balanced UTP cable.

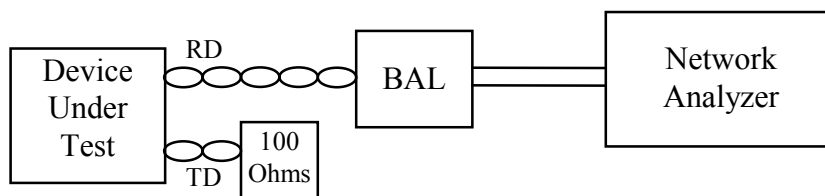


Figure 14.2.4-1: Test Setup F

Procedure:

1. Calibrate the network analyzer with the balun and twisted pair cable between the analyzer and the calibration loads.
2. Connect the RD circuit of the DUT to the twisted pair cable and terminate the TD circuit with a 100 Ω resistive load. Be sure the DUT is powered on.
3. Set the network analyzer to calculate return loss from 5.0 MHz to 10 MHz at its reference resistance.
4. Use the analyzer data to calculate the return loss for reference resistances of 100 Ω , 85 Ω , and 111 Ω .

Observable Results:

- The return loss for the RD circuit must be at least 15 dB below the incident from the range of 5.0 MHz to 10 MHz for each of the reference resistances: 100 Ω , 85 Ω , and 111 Ω .

Test #14.2.4: RD Circuit Link Test Pulse Acceptance

Purpose: To verify that the RD circuit accurately accepts link test pulses.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.11, Test Case ID 1411.10.07
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.1.3.2

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: August 9, 1996

Discussion: Link test pulses have specified characteristics to be recognized by the RD circuits. This test verifies that the station under test shall accept worst-case link test pulses. Worst-case link test pulses have one of the following sets of characteristics:

1. As in Figure 14-12 in IEEE 802.3: with a peak amplitude of 585 mV, a pulse width of 0.60 BT, and maximum undershoot.
2. As in Figure 14-12 in IEEE 802.3: with maximum allowed amplitude of 3.1V, a pulse width of 2.0 BT, and no undershoot.
3. As in Figure 14-12 in IEEE 802.3: with maximum allowed amplitude of 3.1V, a pulse width of 0.6 BT, and maximum undershoot.
4. As in Figure 14-12 in IEEE 802.3: with a peak amplitude of 585 mV, a pulse width of 2.0 BT, and no undershoot.
5. As in Figure 14-12 in IEEE 802.3: with a peak amplitude of 585 mV, a pulse width of 0.6 BT, and no undershoot.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Send a valid packet and monitor the TD circuit.
3. Send at least 11 of the worst case link test pulses to the RD circuit followed by a valid packet and monitor the TD circuit again.
4. Repeat Step 3 using the other worst case link test pulses.

Observable Results:

- After the packet without preceding link test pulses, there shall be no activity on the TD circuit and MAC statistics of the DUT, if available, shall display no packets received.
- The DUT shall accept and, if applicable, reply to the valid packet preceded by each case of 11 worst-case link test pulses.

GROUP 3: LINK INTEGRITY TEST FUNCTIONS

Scope: The following tests cover 10BASE-T operation specific to the functional characteristics of the Link Test functions.

Overview: These tests are designed to verify that the device under test either properly establishes and/or maintains link, or properly remains unlinked based on the test case.

Test #14.3.1: Link Loss Timer

Purpose: To verify that the value of the “link_loss” timer is within the prescribed range.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.7, Test Case ID 1411.07.01
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.7

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: There is a finite time period after link test pulses end that the station under test enters the Link Test Fail state. This time is called “link_loss.” The IEEE 802.3 standard allows the value of “link_loss” to be between 50 ms and 150 ms. This test is designed to determine the value of “link_loss” for the DUT and verify that it is within the specified range.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Use the AWG to generate a series of 11 link test pulses, a delay, and a valid packet.
2. Apply this signal continuously to the RD circuit of the station under test.
3. Monitor the TD circuit of the station under test and/or observe MAC statistics.
4. Vary the delay until reaching the largest value that allows all packets sent to be accepted.
5. Record this delay as the value for “link_loss.”

Observable Results:

- The “link_loss” time shall be between 50 ms and 150 ms.

Test #14.3.2: Acceptance Range of Link Test Pulses

Purpose: To verify the acceptance range of link test pulses.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.7, Test Case ID 1411.07.02
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.7

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: As well as characteristic requirements, link test pulses have requirements for the delay between consecutive pulses. In order to be accepted as valid, received link test pulses shall have a delay between them between “link_test_max” and “link_test_min.” The value for “link_test_min” shall be between 2 ms and 7 ms. The value for “link_test_max” shall be between 25 ms and 150 ms. This test is to verify that the station under test accepts link test pulses with spacing within these ranges.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Verify that the station under test is in the Link Test Fail state.
3. Use the AWG to send at least 11 consecutive link test pulses spaced 7.1 ms apart.
4. Verify that the station under test exits the Link Test Fail state.
5. Repeat procedure using link test pulses spaced 24 ms apart.

Observable Results:

- The station under test shall exit the Link Test Fail state after receiving either set of link test pulses.

Test #14.3.3: Link Test Pulses Outside Acceptance Range (not in Link Test Pass state)

Purpose: To verify the refusal of link test pulses outside the allowed timing range.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.7, Test Case ID 1411.07.04
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.7

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: As well as characteristic requirements, link test pulses have requirements for the delay between consecutive pulses. In order to be accepted as valid, received link test pulses shall have a delay between them between “link_test_max” and “link_test_min.” The value for “link_test_min” shall be between 2 ms and 7 ms. The value for “link_test_max” shall be between 25 ms and 150 ms. This test verifies that the station under test will not accept link test pulses with spacing outside these ranges.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Verify that the station under test is in the Link Test Fail state.
3. Use the AWG to send at least 11 consecutive link test pulses spaced 1.9 ms apart.
4. Verify that the station under test remains in the Link Test Fail state.
5. Repeat procedure using link test pulses spaced 151 ms apart.

Observable Results:

- The station shall not exit the Link Test Fail state.

Test #14.3.4: Value of “lc_max”

Purpose: To find the value of “lc_max.”

References:

- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.3.2.1.7

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: After entering the Link Test Fail State, the station under test shall receive either RD_input or some number of valid link test pulses to return to the Link Test Pass state. The number of link test pulses required is “lc_max” and may be between 2 and 10, inclusively. This test is designed to find the value of “lc_max” for the DUT.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Verify the Link Test Fail state by noticing TP_IDL on the TD circuit.
3. Use the AWG to make a series of 10 valid link test pulses with 16 ms spacing.
4. Send this sequence and verify that the station under test exits the Link Test Fail state.
5. Decrease the number of pulses in the sequence and repeat the procedure.
6. Record the lowest number of pulses that allows the station to exit the Link Test Fail state.

Observable Results:

- The number of pulses needed to exit the Link Test Fail state shall be between 2 and 10 inclusively.

Test #14.3.5: Link Fail Effect on Transmit Functions

Purpose: To verify that, while in the Link Test Fail state, transmit functions are disabled.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.7, Test Case ID 1411.07.05
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.7

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: February 9, 1996

Discussion: For a signal to be accepted, there needs to be a link present between the two stations. A link is recognized by the reception of link test pulses or data on a station's RD circuit, else the station enters the Link Test Fail state. When in this state, transmissions to the TD circuit shall be disabled.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Verify the Link Test Fail state by noticing TP_IDL on the TD circuit.
3. Attempt to send data from the DUT.
4. Observe the TD circuit.

Observable Results:

- The TD circuit shall transmit a TP_IDL message throughout the test.

Test #14.3.6: Link Fail Effect on the Receive Functions

Purpose: To verify that, while in the Link Test Fail state, receive functions are disabled and that the Link Test Pass state is properly entered when receiving data on the RD circuit.

References:

- IEEE Std 1802.3d-1993: Section 6.2.1.7, Test Case ID 1411.07.05
- ANSI/IEEE Std 802.3, 2000 Edition: Section 14.2.1.7, Figure 14-6

Resource Requirements:

- Oscilloscope
- Differential Voltage Probe
- TP Test Card
- Arbitrary Waveform Generator
- Balun

Last Modification: September 6, 1996

Discussion: For a signal to be accepted, there needs to be a link present between the two stations. A link is recognized by the reception of link test pulses or data on a station's RD circuit, else the station enters the Link Test Fail state. When in this state, a valid packet sent to the RD circuit shall not be accepted, but shall cause the station to enter the Link Test Pass state. Thus, a packet immediately following the first packet shall then be accepted. An important exception to this is if the device performs auto-negotiation. As referenced in section 28.2.2.2 and figure 28-17, an auto-negotiating device will not transition to the Link Test Pass state when receiving 10BASE-T data.

Test Setup: See Figure 14.2.2-1.

Procedure:

1. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
2. Verify the Link Test Fail state by noticing TP_IDL on the TD circuit.
3. Send a single packet to the RD circuit of the DUT.
4. Verify that the packet was not accepted by the DUT.
5. Force the RD circuit to enter the Link Test Fail state by stopping any input on the RD circuit for 150 ms or more.
6. Verify the Link Test Fail state by noticing TP_IDL on the TD circuit.
7. Send a series of two packets with an interframe gap of 9.6 μ s to the RD circuit of the DUT.
8. Verify that the second packet was accepted by the DUT.

Observable Results:

- The DUT shall not accept the packet, as it is in the Link Test Fail state. In the series of two packets, the DUT shall not accept the first packet. If the device is not auto-negotiating it shall enter the Link Test Pass state because of RD_input.
- The DUT shall not accept the first packet in the series of two packets, but shall accept the second only if it is not a Clause 28-compliant, auto-negotiating device.

Appendix A: Test Equipment

AWG

An arbitrary waveform generator which matches the specifications in IEEE Std 1802.3d-1993 Section 6.3.4.4 with the exception that the sample resolution shall be 4 ns/point

BAL

100 Ω to 50 Ω balun impedance adapter as defined in IEEE Std 1802.3d-1993 Section 6.3.3.3

Current Probe

Meets specifications defined in IEEE Std 1802.3d-1993 Section 6.3.4.11

Oscilloscope

A digitizing signal analyzer which matches the specifications for an oscilloscope as defined in IEEE Std 1802.3d-1993 Section 6.3.4.8

Differential Voltage Probe

Meets specifications defined in IEEE Std 1802.3d-1993 Section 6.3.4.9

TP Test Card

A testing card with an RJ-45 interface containing the following options:

- Cross over at the input
- Cable termination with 100 Ω load, Test Load 1, or Test Load 2 (as defined in IEEE 802.3 Section 14.3.1.2.1 and Figure 14-11)
- Unshielded twisted pair model (as defined in IEEE Std 802.3 Section 14.3.1.2)
- Link test pulse generator

Appendix B: References

ANSI/IEEE Std 802.3 Fourth Edition, 1993-07-08, Carrier Sense Multiple Access with Collision Detection (CSMA/CD) Access Method and Physical Layer Specifications

IEEE Std 1802.3d-1993, CSMA/CD Access Method and Physical Layer Specifications, Type 10BASE-T Medium Attachment Unit (MAU) Conformance Test Methodology (Section 6), May 5, 1994